

Click [here](https://www.maximintegrated.com/en/storefront/storefront.html) to ask an associate for production status of specific part numbers. **MAX77714 Complete System PMIC, Featuring**

13 Regulators, 8 GPIOs, RTC, and Flexible Power Sequencing for Multicore Applications

General Description

The MAX77714 is a complete power-management IC (PMIC) for portable devices using System-on-Chip (SoC) applications processors.

Two 2A (SD2/3), one 3A (SD1), and one 4A (SD0) stepdown regulator switch at 2MHz, allowing the use of small magnetic components. The output voltages for SD0 and SD1 are programmable from 0.26V to 1.52V in 10mV steps. The output voltage for SD2 is programmable from 0.6V to 2.194V in 6.5mV steps. The output voltage for SD3 is programmable from 0.6V to 3.78V in 12.5mV steps.

Nine low-dropout (LDO) linear regulators supply power to various system blocks. Each LDO features a programmable active-discharge circuit in shutdown. All LDOs feature two soft-start rates to limit inrush current during startup.

Eight programmable GPIOs can be programmed as general purpose inputs (GPI), general purpose outputs (GPO), or alternate modes for additional functionalities.

The real-time clock (RTC) with an external crystal oscillator provides time keeping and alarm wake-up functions. An internal silicon oscillator is available for systems that do not want to use the crystal oscillator. In addition, a watchdog timer is integrated for system monitoring purposes.

An integrated ON/OFF controller, in combination with flexible power sequencer (FPS), provides maximum flexibility in setting power-up/down sequences with minimal intervention from the applications processor.

The 70-bump, 4.1mm x 3.25mm x 0.7mm, 0.4mm pitch wafer-level package (WLP) is ideal for space constrained applications.

Factory-programmable options allow the MAX77714 to be tailored for many applications. Contact the factory for more information about programmable options; minimum order quantities may apply.

Applications

- **Drones**
- Smartphones/Tablet PCs
- **Handheld Gaming Devices**
- **AR/VR Headsets**
- Streaming Devices/Set-Top Boxes
- Home Automation Hubs
- **Digital Cameras**
- **Automotive Aftermarket Accessories**

Benefits and Features

- Highly Integrated
	- 4x Buck Regulators
		- SD0/1 Peak Efficiency > 90% at $3.6V_{\text{IN}}1.1V_{\text{OUT}}$
		- SD2/3 Peak Efficiency > 93% at $3.6V_{\text{IN}}1.8V_{\text{OUT}}$
		- Supports LDDR4x Memory requirements
	- 9x Low-Dropout Linear Regulator
	- Eight GPIOs
	- Real-Time Clock
	- Backup Battery Charger
• Bidirectional Reset I/O
	- Bidirectional Reset I/O
	- Interrupt Output
	- System Watchdog Timer
- Flexible and Configurable
	- I²C-Compatible Interface
	- Factory OTP Options Available
	- Flexible Power Sequencer
	- Configurable Power-Up/Power-Down/Sleep Mode Entry/Exit Timing
	- Highly Configurable GPIO ALT Modes
		- Three Resources Can Be Configured as 32kHz Oscillator Output
		- Four Resources Can Be Configured on FPS
		- One Resource Can Be Configured as ACOK Input
- Low Power
	- Low I_{Ω} of 85µA in Sleep Mode
	- SD0/1 Low-Power Quiescent Current is 10μA
	- SD2/3 Low-Power Quiescent Current is 5μA
	- LDO Low-Power Quiescent Current is 1.5μA
- Small Size
	- 70-Bump, 0.4mm Pitch, 10x7 Ball Array WLP, 4.1mm x 3.25mm x 0.7mm Package Size
	- 230mm² Total Solution Size

[Ordering Information](#page-163-0) appears at end of data sheet. 19-100241; Rev 4; 5/23

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Simplified Block Diagram

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Absolute Maximum Ratings

Note 1: The specified voltage limitation is for steady state conditions. Dead times of a few nano seconds exist as the dynamic stepdown regulator transitions from inductor charging to inductor discharging and vice versa. These dead times allow internal clamping diodes to PGNDx and INBx to forward bias (Vf~1V). When the LXx waveform is observed on a high-bandwidth oscilloscope (≥ 100MHz), the LXx transition edges are commonly seen with 1.5V spikes. These spikes are due to (1) the internal clamping diode forward voltage and (2) the high rate of current change through the current loop's inductance ($V =$ L x di/dt). Designs must follow the recommended printed circuit board (PCB) layout in order to minimize this current loop's inductance.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for *extended periods may affect device reliability.*

Package Information

WLP

For the latest package outline information and land patterns (footprints), go to *www.maximintegrated.com/packages*. Note that a "+", "#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status. Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a four-layer board. For detailed information on package thermal considerations, refer to *www.maximintegrated.com/thermal-tutorial*.

Electrical Characteristics—Global Resources

Electrical Characteristics—Global Resources (continued)

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(Limits are 100% tested at T_A = +25°C. Limits over the operating temperature range (T_A = -40°C to +85°C) and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—ON/OFF Controller

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Flexible Power Supply (FPS)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD0–4A Output)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD0–4A Output) (continued)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD0–4A Output) (continued)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD1–3A Output)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD1–3A Output) (continued)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD2/3–2A Output)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Step-Down Regulators (SD2/3–2A Output) (continued)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—150mA PMOS LDO (LDO2, LDO4, LDO5, LDO6)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A=-40°C to +85°C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—150mA PMOS LDO (LDO2, LDO4, LDO5, LDO6) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1µF, C_{OUT_LDO} = 2.2µF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range ($T_A = 40^\circ \text{C}$ to +85°C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—300mA PMOS LDO (LDO3)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—300mA PMOS LDO (LDO3) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—300mA PMOS LDO (LDO3) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—150mA NMOS LDO (LDO0, LDO1)

(V_{SYS} = 3.7V, V_{IN} _{LDO} = 3.7V, C_{IN LDO} = 1µF, C_{OUT LDO} = 2.2µF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range ($T_A = 40^\circ \text{C}$ to +85°C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—150mA NMOS LDO (LDO0, LDO1) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—300mA NMOS LDO (LDO8)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—300mA NMOS LDO (LDO8) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—450mA NMOS LDO (LDO7)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—450mA NMOS LDO (LDO7) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—450mA NMOS LDO (LDO7) (continued)

(V_{SYS} = 3.7V, V_{IN_LDO} = 3.7V, C_{IN_LDO} = 1μF, C_{OUT_LDO} = 2.2μF. Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range (T_A = $\overline{40^{\circ}}$ C to +85 $^{\circ}$ C) are guaranteed by design and characterization, unless otherwise noted.)

Electrical Characteristics—GPIO

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—GPIO (continued)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—32kHz Oscillator

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—32kHz Oscillator (continued)

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Electrical Characteristics—Backup Battery Charger

(V_{SYS} = 3.6V, T_A = -40°C to +85°C, limits are 100% tested at T_A = +25°C. Limits over the operating temperature range and relevant supply voltage range are guaranteed by design and characterization. Specifications marked "GBD" are guaranteed by design and not production tested.)

Note 2: Design guidance only and is not production tested.

Note 3: Design guidance only and is not production tested.

Note 4: Design guidance only and is not production tested.

Note 5: Individual step-down supply current is not production tested. It is covered by a combined test by turning on all step-down regulators.

Note 6: There is an n-channel MOSFET in series with the output active discharge resistance. This NMOS requires V_{SYS} > 1.2V to be enhanced.

Note 7: The ramp-down slew rate when the output voltage is decreased via I²C is a function of the negative current limit and the output capacitance. With no load, forced PWM mode, and 22µF output capacitor, the ramp-down slew rate is dv/dt = i / C = 0.4A / 22μ F = 18mV/ μ s.

- **Note 8:** DVS and soft-start ramp rates can be expected to vary by up to 30%.
- **Note 9:** The input and output voltage range of SD2/3 ensure that the 90% duty cycle limitation can never practically be reached. Additionally, SD2/3 is capable of 100% duty cycle for output voltages above 1.9V.
- Note 10: Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range are guaranteed through correlation using statistical quality control methods.
- **Note 11:** Does not include ESR of the capacitance or trace resistance of the PCB.
- **Note 12:** Limits are 100% production tested at $T_A = +25^{\circ}$ C. Limits over the operating temperature range are guaranteed through correlation using statistical quality control methods.
- **Note 13:** Does not include ESR of the capacitance or trace resistance of the PCB.
- Note 14: Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range are guaranteed through correlation using statistical quality control methods.
- **Note 15:** Does not include ESR of the capacitance or trace resistance of the PCB.
- Note 16: Limits are 100% production tested at T_A = +25°C. Limits over the operating temperature range are guaranteed through correlation using statistical quality control methods.
- **Note 17:** Does not include ESR of the capacitance or trace resistance of the PCB.
- **Note 18:** Does not include ESR of the capacitance or trace resistance of the PCB.
- Note 19: During a soft-start event or a DVS transition, the regulators output current increases by C_{OUT} x dV/dt. In the event that the
load current plus the additional current imposed by the soft-start or DVS transition current limit is enforced. When the current limit is enforced, the advertised transition rate (dV/dt) does not occur.
- **Note 20:** Guaranteed by $V_{\text{I}H}$ and $V_{\text{I}L}$ tests.
- **Note 21:** Minimum supply for basic functionality with reduced accuracy.
- **Note 22:** Includes 3pF of parasitic capacitance on XIN and XOUT.
- **Note 23:** Number of valid cycles the frequency detector needs to count before it asserts OK32K.

Typical Operating Characteristics

 $(AV_{VDD} = +3.3V, V_{DDIO} = +1.8V, V_{REFP} - V_{REFN} = V_{REF} = 2.5V; No Line-Frequency Rejection, Continuous-Conversion Mode, Internal$ Clock; $T_A = T_{MIN}$ to T_{MAX} unless otherwise noted.)

OUTPUT VOLTAGE (V)

Typical Operating Characteristics (continued)

(AV_{VDD} = +3.3V, V_{DDIO} = +1.8V, V_{REFP} - V_{REFN} = V_{REF} = 2.5V; No Line-Frequency Rejection, Continuous-Conversion Mode, Internal Clock; $T_A = T_{MIN}$ to T_{MAX} unless otherwise noted.)

Typical Operating Characteristics (continued)

 $(AV_{VDD} = +3.3V, V_{DDIO} = +1.8V, V_{REF} - V_{REF} = V_{REF} = 2.5V; No Line-Frequency Rejection, Continuous-Conversion Mode, Internal$ Clock; $T_A = T_{MIN}$ to T_{MAX} unless otherwise noted.)

Typical Operating Characteristics (continued)

 $(AV_{VDD} = +3.3V, V_{DDIO} = +1.8V, V_{REFP} - V_{REFN} = V_{REF} = 2.5V; No Line-Frequency Rejection, Continuous-Conversion Mode, Internal$ Clock; $T_A = T_{MIN}$ to T_{MAX} unless otherwise noted.)

Typical Operating Characteristics (continued)

 $(AV_{VDD} = +3.3V, V_{DDIO} = +1.8V, V_{REF} - V_{REF} = V_{REF} = 2.5V; No Line-Frequency Rejection, Continuous-Conversion Mode, Internal$ Clock; $T_A = T_{MIN}$ to T_{MAX} unless otherwise noted.)

Bump Configuration

MAX77714

Bump Description

Bump Description (continued)

Bump Description (continued)

Bump Description (continued)

Detailed Description

OTP Options

Refer to **Table 1** for the default register settings.

Table 1. OTP Options

Table 1. OTP Options (continued)

Detailed Description—Global Resources

Voltage References, Bias Currents, and Timing References

Centralized voltage references, bias current, and timing references support all of the functional blocks within the MAX77714. These resources are automatically enabled when any of the peripheral functions within the device require them. The supply current associated with the minimum set of these resources make up the quiescent current (I_Q MBATT).

Voltage Monitors

The MBATT undervoltage lockout (UVLO) and MBATT overvoltage lockout (OVLO) comparators force the entire device off when the supply voltage (V_{MRATT}) is not within the acceptable window of operation. Disabling the device when the supply is outside of its acceptable range ensures reliable consistent behavior when the supply voltage is removed/ applied and prevents overvoltage stress to the device. The main-battery low signal is also available through the nRST_IO signal when LBRSTEN = 1. With all peripheral blocks of the device disabled, the quiescent current of the device is $12\mu A$ (IQ_MBATT).

Thermal Monitors

Several on-chip thermal sensors force the device to shutdown if the junction temperature exceeds +165°C (TJSHDN). In addition to the +165°C shutdown threshold, these thermal sensors also provide interrupts when the temperature exceeds +120°C (thermal alarm 1) and +140°C (thermal alarm 2).

Bidirectional Reset Input/Output

The device has a bidirectional, active-low, open-drain, reset input/output (nRST_IO). The RSO signal within the bidirectional reset IO logic is asserted by the device when it needs to drive nRST_IO low. If the device is not driving nRST_IO low (i.e., RSO is low), and an external device such as a reset button pulls nRST_IO low, then the RSI signal within the bidirectional reset IO logic is asserted. If RSI is asserted for longer than t_{DBNC} , then a global shutdown event is triggered (GLBALSHDN). A global shutdown due to RSI is recorded in the POERC register such that when the system's microprocessor recovers from the reset it can recognize that the cause of the power down was due to RSI. If a global shutdown event is triggered by RSI, then the deviceautomatically generates a wakeup event after the global shutdown event has completed.

The reset output is a programmable slave to the flexible power sequencer. Allowing the RSO to respond to the flexible power sequencer gives it the capability to drive the nRST_IO line low as the first action in the power down sequence. The RSTIOFPS register configures how nRST_IO behaves with respect to the flexible power sequencer.

Once all conditions for allowing the reset output to go high-impedance have been met, a reset delay timer is initiated before RSO is deasserted (t_{RST-O}).

The following bulleted list summarizes all the conditions required for the device to set RSO low and allow nRST_IO to go high-impedance.

- The device must not be in a global shutdown state.
- The 32kHz oscillator must be stable (32K_OK).
- The flexible power sequencer (FPS_RSO) must be satisfied.
- Reset timer has expired (t_{RST} \bigcirc).

An example configuration that allows nRST_IO to go high-impedance is:

- No global shutdown events.
- The main-battery voltage is within the valid region.
- The 32kHz clock is stable.
- FPS0 (flexible power sequencer 0) has gotten past power-up cycle 4 (FPS_RSO).
- t_{RST_O} expired.
- No external device such as a reset button are pulling nRST_IO low.

Figure 1. Global Resource Logic

Global Shutdown

This document uses the term "global shutdown" to refer to any event that causes a shutdown of all regulators and a reset for most of the registers within the device. The POERC register records the source of a "global shutdown" event. The various conditions which cause a global shutdown are as follows:

- \bullet The battery voltage is low (MBATT < MBATT_RESET falling)
- Hardware reset input (RSI) event detected
- Manual Reset event detected
- Watchdog timer expires
- SFT_RST = 1
- PWR OFF = 1
- The junction temperature is too high $(T_{\rm J} > T_{\rm JSHDN})$
- SHDN pin is asserted (SHDN = 1)
- SRCFPS0 = 1 and ENFPS0 register transitions from HIGH to LOW

After a global shutdown occurs, the device can be powered up normally as long as the main-battery voltage and the die temperature are within their valid ranges. Although all regulators are forced off in response to a global shutdown, the RTC remains powered and continues to record the calendar.

From any state in the device, there are three ways of implementing a "global shutdown". The source of the global shutdown event determines how a global shutdown is implemented as described in the following:

Global Shutdown Events with Sequenced Shutdown and Automatic Wakeup

The events in this category are associated with faulty system states where the software may not be working properly but the system could potentially recover by powering down the microprocessor, resetting all the global shutdown registers, and then powering up the microprocessor again. The following events initiate a sequenced shutdown followed by automatic wakeup:

- RSI event (hardware reset input)
- SFT_RST event if SFT_RST_WK = 1 (software reset input)
- Watchdog timer expires if WD_RST_WK = 1
- \bullet Manual reset event if OTP MR = 1

Global Shutdown Events with Sequenced Shutdown to the OFF State

Six events initiate "sequenced global shutdown to the off state." With the exception of PWR_OFF, which is a normal system function, the events in this category are associated with undesirable system states that may occur in a normally functioning product. Powering down the microprocessor and resetting all the global shutdown registers helps the system resolve these undesirable events. In general, a wakeup event such as an onkey press is required to power-up the microprocessor again.

In the case of a software reset input (SFT_RST) with SFT_RST_WK = 0, the global shutdown state machine results in the default state with the device off and waiting for a wakeup event. It is possible for the system software to program a wakeup event based on an RTC alarm. For example, once the state machine lands in the default state it waits there until the RTC alarm generates the wakeup event.

The following six conditions fall into this category:

- Watchdog timer expires if WD_RST_WK = 0
- Manual reset event if OTP_MR = 0
- SFT_RST event if SFT_RST_WK = 0 (software reset input)
- \bullet PWR OFF = 1
- TJ > TJSHDN (thermal overload)
- SHDN input event

Global Shutdown Events with Immediate Shutdown

Four events initiate an "immediate shutdown." The events in this category are associated with potentially hazardous system events. Powering down the microprocessor and resetting all the registers helps mitigate any issues that may

occur due to these potentially hazardous system events.

The following four events fall in this category:

- V_{MBATT} < V_{MBATTUVLO} (main-battery undervoltage)
- V_{MBATT} > V_{MBATTOVLO} (main-battery overvoltage)
- $OK32K = 0$ (in or after standby state)
- $BRDY = 0$ (in or after ready state)

System Watchdog Timer

The MAX77714 contains a system watchdog timer to ensure safe and reliable operation. The system watchdog timer prevents the device from powering a system in the event that the system controller (processor) hangs or otherwise isn't communicating correctly. The default state of the system watchdog timer enable bit (WDTEN) can be factory programmed with an OTP bit (OTP_WDTEN). To use the watchdog timer feature, enable the feature by setting WDTEN. While enabled, the system controller must reset the system watchdog timer within the timer period (t_{WD}) for the charger to operate normally. Reset the system watchdog timer by programming WDTC[1:0] = 0b01. t_{WD} is programmable from 2s to 128s with TWD[1:0].

With WDTEN set, an internal counter is incremented with the internal oscillator. When the internal counter matches a value programmed by TWD[1:0], the device asserts nRST_IO, powers down all of its regulators with a global shutdown condition, and sets the WDT bit in the non-volatile event recorder.

To prevent the system watchdog timer from initiating a global shutdown event and disabling the device, a properly operating processor clears the system watchdog timer within the timer period programmed by TWD[1:0]. The system watchdog time is cleared by setting WDTC[1:0] = 0b01.

The system watchdog timer can be set to automatically clear when the AP enters its sleep or off states. The device interprets the AP sleep state as FPS1 being disabled. The device interprets the off state as FPS1 being disabled.

Note that the device contains both a system watchdog timer and an I2C watchdog timer.

Figure 2. System Watchdog Timer

EN0 Functionality

The EN digital input can be configured to work with a push-button switch, a slide-switch, or a ON/OFF logic signal (e.g., PGOOD). [\(Figure 3](#page-45-0)) shows EN's functionality for power-on sequencing and manual reset. Applications that use a slideswitch on-key or ON/OFF logic signal configuration must set OTP_EN0[1:0]. The polarity of EN0 can be controlled using the OTP_EN0AL bit.

Figure 3. EN0 Functionality Options

Interrupt Logic

Several interrupt and interrupt mask registers monitor key information and assert the nIRQ output signal when an interrupt event has occured. nIRQ is an active-low, open-drain output that is typically routed to the processor's interrupt input to allow for quick notification of interrupt events. A pullup resistor is require for this signal. This pullup resistor is typically found inside the processor that interprets the interrupt signal, but a board-mounted pullup resistor is required if one is unavailable.

Figure 4. Simplified Interrupt Status and Mask Logic

Detailed Description—ON/OFF Controller

ON/OFF Controller

The ON/OFF controller monitors multiple wakeup sources to intelligently enable all resources that are necessary for the AP to boot (i.e., FPS0 and FPS1). The ON/OFF controller monitors wakeup events on the EN0, EN1, ACOK, and nRST_IO hardware inputs. Additionally, internal wakeup events are also monitored: SMPL, ALARM1, and ALARM2 internal signals. Wakeup events go through logic to affect flexible power sequencers 0 and 1 (FPS0, FPS1). Many wakeup signals can be masked (WK_ACOK, WK_ALARM1, WL_ALARM2, WK_EN0).

Many signals within the ON/OFF controller generate interrupts and are recorded in the status registers.

Figure 5. State Diagram: ON/OFF Controller Top Level

Table 2. ON/OFF Controller Transition Conditions

Table 2. ON/OFF Controller Transition Conditions (continued)

Power-Up/Down Sequence

The device integrated a flexible power sequencer (FPS) that controls the power-up and power-down timing of the system. The functionality of the FPS is described as follows:

- The power-up/down sequence consists of two FPS masters (FPS0 and FPS1) each contains 8 slots.
- The 8 slots count sequentially in time during both power-up and power-down.
- During the power-up sequence (Figure 6), the slots count upwards from 0 to 7.
- During the power-down sequence [\(Figure 7](#page-50-0)), the slots count downwards from 7 to 0.
	- The events in this category are associated with faulty system states where the software may not be working properly but the system could potentially recover by powering down the microprocessor, resetting all the global shutdown registers, and then powering up the microprocessor again.
- Regulators enable in their assigned slots in the power-up sequence. Regulators disabled in their assigned slots in the power-down sequence.
- GPIOs assert logic-high in their assigned slot in the power-up sequence. GPIOs assert logic-low in their assigned slot in the power-down sequence.
- Three dedicated bits are available to program the slot pitch (t_{FPST} , time between slots) and are programmable between 31μs to 3904μs in eight binary weighted steps.
	- FPS0 power-up sequence (MSTR_PU[2:0]), power-down sequence (MSTR_PD[2:0]).
	- FPS1 sleep exit power-up sequence (MSTR_SLPEXT[2:0]), Sleep entry power-down sequence (MSTR_SLPENTY[2:0]).

Figure 6. Flow Chart—Power-Up Sequence

Figure 7. Flow Chart—Power-Down Sequence

Immediate Shutdown

The events in this category are associated with potentially hazardous system events. Powering down the microprocessor and resetting all the device registers helps mitigate any issues that may occur due to these potentially hazardous system events.

Figure 8. Flow Diagram: Immediate Shutdown

RESET

The reset state puts the PMIC in an initial known state by following the flow in ([Figure 9](#page-52-0)).

Figure 9. Reset Flow Diagram

EN0

EN0 is a digital input to the ON/OFF controller that typically comes from the system's on-key. EN0 is factoryprogrammable with OTP (OTP_EN0[1:0]) to either be push-button mode, slide switch mode, or On/Off software mode. The EN0 polarity is factory-programmable with OTP (OTP_EN0AL) to be active-high or active-low.

EN1

EN1 is a digital input to the ON/OFF controller that typically comes from the system's AP. EN1 is used to control sleep modes. The EN1 polarity is factory-programmable with OTP (OTP_EN1AL) to be active-high or active-low.

ACOK

ACOK is a digital input (GPIO3 ALT mode) to the ON/OFF controller that typically comes from the system's battery charger. ACOK indicates the presence/absence of the external charge adapter. The ACOK polarity is factoryprogrammable with OTP (OTP_ACOKAL) to be active-high or active-low with the appropriate internal pull-up/down.

SHDN

The shutdown input (SHDN) is a digital input to the ON/OFF controller that causes the device to reset through a global shutdown event. The signal for SHDN typically comes from a temperatures sensor such as the MAX6642 that measures the internal die temperature of the AP. The SHDN polarity is factory-programmable with OTP (OTP_SHDNAL) to be active high or active low with the appropriate internal pull-up/down. A system shutdown based on SHDN is recorded in the non-volatile power-off event recorder.

SMPL, ALARM1, and ALARM2

SMPL, ALARM1, and ALARM2 are signal generated from the RTC and used by the ON/OFF controller. See the *[RTC](#page-73-0)* section for more information on these signals.

MBATT_OK and MBATTLOW

MBATT_OK and MBATTLOW are digital signals that come from the systems' main-battery monitor. MBATT_OK gates several wakeup sources so that they cannot enable FPS0 and FPS1 until the battery is above the system undervoltagelockout threshold (V_{MBATTUVLO}). MBATTLOW prevents FPS0 and FPS1 from being enabled when the main-battery is below a programmed minimum voltage.

Resource Power Mode

Table 3. LDO and Step-Down Resource Power Mode

Table 4. 32k Resource Power Mode

Table 4. 32k Resource Power Mode (continued)

Detailed Description—Flexible Power Supply (FPS)

Power-Off Event Recorder

Several events within a MAX77714 based system can autonomously cause a power-off (i.e., global shutdown). The source of the power-down event is recorded in a register so that when the system's microprocessor powers on again it can determine the source of the previous power-off condition. This power-off event recorder register is non-volatile as long as the RTC's coin cell (BBATT) remains within its valid voltage range. Unlike most interrupt registers, the POERC register does not have a corresponding interrupt mask and status register. Additionally, it does not affect the nIRQ pin. No status register is provided since all POERC events result in a global shutdown which would subsequently reset any related status. Once a bit is set, the controller has to write a 1 to clear it.

Flexible Power Sequencer (FPS)

The FPS allows each regulator to power-up under hardware or software control. Additionally, each regulator can power on independently or among a group of other regulators with an adjustable power-up and power-down delays (sequencing). GPIO0, GPIO1, GPIO2, and GPIO7 can be programmed to be part of a sequence allowing external regulators to be sequenced along with internal regulators. nRST_IO can be programmed to be part of a sequence.

[\(Figure 10](#page-55-0)) shows LDO0, LDO1, LDO2, and LDO3 powering up under the control of flexible power sequencer 2.

The time period between each sequencer event for power-up, power-down, sleep entry, and sleep exit can be configured by setting MSTR_PU[2:0], MSTR_PD[2:0], MSTR_SLPENTY[2:0], and MSTR_SLPEXT[2:0] respectively.

The flexible sequencing structure consists of two hardware enable inputs (EN0, EN1), and three master sequencing timers. Each master-sequencing timer is programmable through its configuration register to have a hardware enabled source or a software enabled source (CNFG_GLBLx). When enabled/disabled the master-sequencing timer generates eight sequencing events. The time period between each event is programmable within the configuration register.

Each regulator, GPIO0, GPIO1, GPIO2, GPIO7 and nRST_IO has a flexible-power-sequence slave register (FPS_x) which allows its enable source to be specified as a flexible-power-sequence timer or a software bit. When a FPSSRCx specifies the enable source to be a flexible power sequencer, the power-up and power-down delays are configured by MSTR_PU[2:0] and MSTR_PD[2:0] and can be specified in that regulator's flexible-power-sequencer configuration register.

If any of the FPS hardware inputs (EN0, EN1) are not needed, connect them to ground. Grounding these inputs when they are not needed ensures that they do not accidentally turn on any voltage regulators—furthermore it improves the thermal impedance of the MAX77714 package.

Figure 10. Flexible Power Sequencer

Features

- **Two Sequencers**
- Power-Up/Down Sequencing Control
- **Eight Power-Up Sequence Time Slots**
- **Eight Power-Down Sequence Time Slots**
- Adjustable Time Period Between Time Slots from 31µs to 3,904µs in Eight Binary Weighted Steps
- Sequence Enable/Disable can be Controlled by Hardware and Software
- Capable of Controlling:
	- All Regulators
	- GPIO0, GPIO1, GPIO2, and GPIO7
	- nRST_IO

FPS0

Flexible Power Sequencer 0 is the enable signal for the resources that need to be enabled when the AP is in its normal operating mode and its sleep mode. When the AP is in normal operating mode, both FPS0 and FPS1 are enabled.

FPS1

Flexible Power Sequencer 1 is the enable signal for the resources that need to be enabled when the AP is in its normal operating mode **and disabled when the AP is in sleep mode.** When the AP is in normal operating mode, both FPS0 and FPS1 are enabled.

FPS Sequence Power-Up/Down

Figure 11. FPS Sequence Power-Up/Down

FPS Sequence Sleep Entry/Exit

Figure 12. FPS Sleep Entry/Exit

Detailed Description—Step-Down Regulators (SD0–4A Output)

SD0 is a step-down converter with the following features:

- Programmable output voltage from 0.26V to 1.52V in 10mV steps.
- \bullet \pm 2% Initial output accuracy.
- Capable of 4A continuous output current.
- Capable of powering up into a prebiased output.
- Automatic transition from pulse-skipping mode to fixed-frequency mode to provide high efficiency across load range.
- Programmable low-power-mode (LPM) to enable efficient low-power PMIC states.
- Programmable soft-start to minimize inrush current.
- Inductor current limits to limit power output to a short circuit or overload.
- Capable of active discharge.
- Programmable brownout and over-voltage comparators.

Active Discharge

● When the active discharge feature is enabled (SD0ADDIS = 0) and the step-down is disabled (either through I²C or by the sequencer), there is a 100 Ω active discharge resistance that is enabled from the output to ground.

Output Monitoring

SD0 has multiple ways of ensuring the health of its output.

- There is a programmable brownout monitor that sets an interrupt flag (SD0 UV I) when the output voltage falls below the programmed brownout threshold.
	- If the SD0 UV M mask bit is unmasked, this allows the brownout on the output of the step-down to initiate a powerdown sequence.
	- When the step-down is first enabled, either through $1²C$ or by the sequencer, the brownout condition is not be asserted until the soft-start is complete. However, if the output capacitance is large enough, the soft-start process completes before the output reaches the rising UV threshold and thereby the UV interrupt would get set, although the output would eventually rise above the UV threshold.
	- However, when the output voltage target is increased through I2C (write to SD0VOUT[6:0]) and the step-down converter is in the process of performing the controlled ramp to the new target, a brownout condition is not triggered until the controlled ramp is complete.
- There is a programmable overvoltage monitor that sets an interrupt flag (SD0_OV_I) when the output voltage rises above the programmed overvoltage threshold.
	- If the SD0 OV M mask bit is unmasked, this allows the overvoltage on the output of the step-down to initiate a power-down sequence and assert the nIRQ output.
	- However, when the output voltage target is decreased through I²C (write to SD0VOUT[6:0]) and the step-down converter is in the process of performing the controlled ramp to the new target (if SD0FSREN = 1), an overvoltage condition is not triggered until the controlled ramp is complete. Note that if the controlled ramp for decreasing output voltage target is disabled (SD0FSREN = 0), then the over-voltage condition triggers and causes a power down sequence if unmasked (SD0_OV_M = 0). If this situation is expected, it is recommended to mask it by setting SD0_OV_M to 1.
	- When the step-down is first enabled, either through 1^2C or by the sequencer, it is possible that the combination of the programmed soft-start ramp rate (SD0SSRAMP) and the output capacitance is such that it can cause the inductor current to reach the PMOS peak current limit.
	- Similarly, when the output voltage target is increased (by a write to SD0VOUT[6:0]) and the slew rate for dynamic voltage scaling is high enough (SD0SSRAMP), it can cause the inductor current to reach the PMOS peak current limit.
- All of the above conditions have associated status bits that provide a real-time status of the condition.

Enable and Power Mode Control

- SD0 can be enabled and disabled either by the flexible power sequencer or by I²C.
- The SD0FPS register configures if it is part of the sequence, and the master and slots numbers that it is assigned to.
- The bits PWR_MD_SD0[1:0] control whether the step-down is in normal-power mode or low-power mode.
- The step-down can be configured to dynamically transition to low-power mode when the PMIC transitions to the DevSlp state.
- The step-down can also be forced to transition to low-power mode through an ${}^{12}C$ command. See ([Table 3\)](#page-53-0) in the Resource Power Mode section for additional information.

PCB Layout Guidelines

Careful circuit board layout is critical to achieve low-switching power losses and clean, stable operation.

When designing the PCB, follow these guidelines:

- 1. Place the inductor and output capacitor close to the device and keep the loop area of switching current small.
- 2. When wiring the high current paths, short and wide traces should be used. For example, the trace between LX and the inductor. The voltage on this node is switching very quickly and additional area creates more radiated emissions.
- 3. The ground loop for the input and output capacitor should be as small as possible.
- 4. AGND should be connected to PGND through a via. Connect DGND and AGND together at the return terminal of the output capacitor. Do not connect them anywhere else.
- 5. Keep the power traces and load connections short and wide. This practice is essential for high-efficiency.
- 6. The feedback pin should be routed away from the switching node to increase noise immunity. This pin is a highimpedance input which is highly noise sensitive.
- 7. When possible, ground planes and traces should be used to help shield the feedback signal and minimize noise and magnetic interference.

Detailed Description—Step-Down Regulators (SD1–3A Output)

SD1 is a step-down converter with the following features:

- Programmable output voltage from 0.26V to 1.52V in 10mV steps.
- \bullet \pm 2% Initial output accuracy.
- Capable of 3A continuous output current.
- Capable of powering up into a prebiased output.
- Automatic transition from pulse-skipping mode to fixed-frequency mode to provide high-efficiency across load range.
- Programmable low-power mode (LPM) to enable efficient low-power PMIC states.
- Programmable soft-start to minimize inrush current.
- Inductor current limits to limit power output to a short circuit or overload.
- Capable of active discharge.
- Programmable brownout and over-voltage comparators.

Active Discharge

● When the active discharge feature is enabled (SD1ADDIS = 0) and the step-down is disabled (either through I²C or by the sequencer), there is a 100 Ω active discharge resistance that is enabled from the output to ground.

Output Monitoring

SD1 has multiple ways of ensuring the health of its output.

- There is a programmable brownout monitor that sets an interrupt flag (SD1 UV I) when the output voltage falls below the programmed brownout threshold.
	- If the SD1_UV_M mask bit is unmasked, this allows the brownout on the output of the step-down to initiate a powerdown sequence.
	- When the step-down is first enabled, either through ${}^{12}C$ or by the sequencer, the brownout condition is not asserted until the soft-start is complete. However, if the output capacitance is large enough, the soft-start process completes before the output reaches the rising UV threshold and thereby the UV interrupt would get set, although the output would eventually rise above the UV threshold.
	- However, when the output voltage target is increased through I2C (write to SD1VOUT[6:0]) and the step-down converter is in the process of performing the controlled ramp to the new target, a brownout condition is not triggered until the controlled ramp is complete.
- There is a programmable overvoltage monitor that sets an interrupt flag (SD_OV_I) when the output voltage rises above the programmed overvoltage threshold.
	- If the SD1_OV_M mask bit is unmasked, this allows the overvoltage on the output of the step-down to initiate a power-down sequence and assert the nIRQ output.
	- However, when the output voltage target is decreased through I²C (write to SDVOUT[6:0]) and the step-down

converter is in the process of performing the controlled ramp to the new target (if SD1FSREN = 1), an overvoltage condition is not triggered until the controlled ramp is complete. Note that if the controlled ramp for decreasing output voltage target is disabled (SD1FSREN = 0), then the over-voltage condition triggers and could cause a powerdown sequence if unmasked (SD1_OV_M = 0). If this situation is expected, it is recommended to mask it by setting SD1_OV_M to 1.

- When the step-down is first enabled, either through $12C$ or by the sequencer, it is possible that the combination of the programmed soft-start ramp rate (SD1SSRAMP) and the output capacitance is such that it can cause the inductor current to reach the PMOS peak current limit.
- Similarly, when the output voltage target is increased (by a write to SD1VOUT[6:0]) and the slew rate for dynamic voltage scaling is high enough (SD1SSRAMP), it can cause the inductor current to reach the PMOS peak current limit.
- All of the above conditions have associated status bits that provide a real-time status of the condition.

Enable and Power Mode Control

- SD1 can be enabled and disabled either by the flexible power sequencer or by 1^2C .
- The SD1FPS register configures if it is part of the sequence, and the master and slots numbers that it is assigned to.
- The bits PWR_MD_SD1[1:0] control whether the step-down is in normal-power mode or low-power mode.
- The step-down can be configured to dynamically transition to low-power mode when the PMIC transitions to the DevSlp state.
- The step-down can also be forced to transition to low-power mode through an 1^2C command. See ([Table 3\)](#page-53-0) in the *Resource Power Mode* section for additional information.

Detailed Description—Step-Down Regulators (SD2/3–2A Output)

SD2 and SD3 are step-down converters with the following features:

- Programmable output voltage from 0.600V to 2.194V in 6.25mV steps for SD2.
- Programmable output voltage from 0.600V to 3.78V in 12.5mV steps for SD3.
- \bullet \pm 2% Initial output accuracy.
- Capable of 2A continuous output current.
- Capable of powering up into a prebiased output.
- Automatic transition from pulse-skipping mode to fixed-frequency mode to provide high-efficiency across load range.
- Programmable low-power mode (LPM) to enable efficient low-power PMIC states.
- Soft-start to minimize inrush current.
- Inductor current limits to limit power output to a short circuit or overload.
- Programmable brownout and over-voltage comparators.

Output Monitoring

SD2 and SD3 have multiple ways of ensuring the health of their output.

- There is a programmable brownout monitor that sets an interrupt flag (SD2_UV_I/SD3_UV_I) when the output voltage falls below the programmed brownout threshold.
	- If the SD2 UV M/SD UV M mask bit is unmasked, this allows the brownout on the output of the stepdown to initiate a power-down sequence.
	- When the step-down is first enabled, either through ${}^{12}C$ or by the sequencer, the step-down's control circuit attempts to ramp the output voltage as fast as possible to the target output (programmed by SDVOUT[7:0]/SD3VOUT[7:0]) limited only by the PMOS peak current limit. During this process of output voltage ramp, the brownout output is prevented from being triggered until the end of the soft-start period (determined by the specified ramp-up slew rate). However, if the output capacitance is large enough, the soft-start process completes before the output reaches the rising UV threshold and thereby the UV interrupt would get set, although the output would eventually rise above the UV threshold.
	- When the output voltage for SD2 or SD3 is increased through 1^2C (programmed by SD2VOUT[7:0]/SD3VOUT[7:0]) after they have been enabled, the step-down control circuit changes the

output voltage target directly to the final value. In such a case, the brownout comparator provides an undervoltage assertion. If the undervoltage assertion is not masked by SD2_UV_M/SD3_UV_M, a powerdown sequence occurs. If such a use case is foreseen, it is recommended to set the mask bits first and then change the output voltage. Alternatively, the change in output voltage should be done in small steps. Note that even if the mask bit is set, the corresponding interrupt bit is still set.

- Note that a load transient on the output of the step-down at a fast slew rate and a large magnitude has the capability to cause an output voltage droop that can cause the UV comparator to trip and flag an undervoltage event, if the brownout threshold is set high (such as 90%).
- There is a programmable overvoltage monitor that sets an interrupt flag (SD2_OV_I/SD3_OV_I) when the output voltage rises above the programmed overvoltage threshold.
	- If the SD2, OV, M/SD3, OV, M mask bit is unmasked, this allows the overvoltage on the output of the stepdown to initiate a power-down sequence.
	- When the step-down is first enabled, either through 1^2C or by the sequencer, the step-down control circuit attempts to ramp the output voltage as fast as possible to the target output (programmed by SD2VOUT[7:0]/SD3VOUT[7:0]) limited only by the PMOS peak current limit. During this process of output voltage ramp, the over-voltage output is prevented from being triggered until the end of the soft-start period (determined by the specified ramp-up slew rate).
	- When the output voltage for SD2 or SD3 is increased through I2C (programmed by SD2VOUT[7:0]/SD3VOUT[7:0]) after they have been enabled, the step-down's control circuit changes the output voltage target directly to the final value. The step-down output voltage increases as a function of the output capacitance and load. In such a case, the over-voltage comparator provides an overvoltage assertion. If the overvoltage assertion is not masked by SD1_OV_M/SD1_OV_M, a power-down sequence occurs. If such a use case is foreseen, it is recommended to set the mask bits first and then change the output voltage. Alternatively, the change in output voltage should be done in small steps. Note that even if the mask bit is set, the corresponding interrupt bit is still set.
	- Note that a sudden load release with a high slew rate and magnitude has the potential to cause a momentary over-shoot on the output of the step-down that can trip the OV comparator output. If such use cases are expected, the OV threshold should be set as high as allowed.
- All of the above conditions have associated status bits that provide a real-time status of the condition.

Enable and Power Mode Control

- SD2/3 can be enabled and disabled either by the flexible power sequencer or by 1^2C .
- The SD2FPS/SD3FPS registers configure if it they are part of the sequence, and the master and slots numbers that they are assigned to.
- The bits PWR_MD_SD2[1:0]/PWR_MD_SD3[1:0] control whether the step-down is in normal-power mode or lowpower mode.
	- The step-down can be configured to dynamically transition to low-power mode when the PMIC transitions to the DevSlp state.
	- The step-down can also be forced to transition to low-power mode through an 1^2C command. See (Table [3\)](#page-53-0) in the *Resource Power Mode* section for additional information.

Active Discharge Resistor

SD2/3 have an active-discharge resistance that can be enabled and disabled with SDxADDIS. Enabling the active discharge feature helps ensure a complete and timely power-down of all system peripherals. The default condition of the active-discharge resistor feature is enabled, such that when the step-down converter is disabled, an internal 100Ω discharge resistor is connected to the output to discharge the energy stored in the output capacitor. When the step-down converter is enabled, the discharge resistor is disconnected from the output.

Soft-Start

The SD2/3 regulators have a soft-start feature to limit the inrush current during startup. The soft-start feature is achieved by limiting the slew rate of the output voltage during startup ($dV_{\text{OUT}}S_{\text{DX}}/dt$).

During soft-start the output voltage for the regulator ramps at a fixed rate of 17mV/μs to its final value. The soft-start

time(μ s) is calculated by V_{OUT} $SDx/17mV$. If V_{OUT} $SDx = 1.8V$, the startup time is 105µs.

Register and Reset Conditions

See the *[PMIC Register](#page-91-0)* section for additional information.

Detailed Description—150mA PMOS LDO (LDO2, LDO4, LDO5, LDO6)

The MAX77714 has nine linear regulators (LDOs).

The four NMOS regulators are capless designs that are stable with or without an output decoupling capacitor. Additionally, the PMOS regulators have adjustable compensation that allows for the use of remote output capacitors.

All regulators can be operated in low-power mode, where the no-load quiescent current drops to 1.5mA. In low-power mode, each output supports a maximum load of 5mA.

All regulators have an output voltage power-OK interrupt signal that is integrated into the MAX77714 interrupt architecture.

Features and Benefits

- Nine Linear Regulators
	- General Performance
		- ±3% Output Accuracy LDOx and ±4.5% for LDO4 (0.4V) Over Load/Line/Temperature
		- 50mV Dropout at Full Load
		- 63dB PSRR at 10kHz
		- 1.5mA Low-Power Mode
		- Short-Circuit and Thermal-Overload Protection
		- Dynamically Programmable Output Voltage
		- Power-OK Interrupt
		- Programmable Soft-Start Rate: 100mV/μs or 5mV/μs
	- Soft-Start into Prebiased Output
	- Four N-Channel Regulators (LDO0/1/7/8)
		- 0.8V to 5.5V Input Range
		- 29mA Quiescent Supply Current
		- No Output Capacitor Required in Normal Operating Mode (cap required for low-power mode)
	- Five Standard P-Channel Regulators (LDO2/3/4/5/6)
		- 1.7V to 5.5V Input Range
		- 20mA Quiescent Supply Current
		- Remote Capacitor Design with Register Adjustable Compensation to Optimize Transient Performance

Simplified Block Diagram

The nine LDOs of the MAX77714 are derived of five basic topologies as shown in [\(Table 5](#page-63-0)).

The PMOS regulators (PDRVx) operate and draw power from their power inputs (IN_LDOxx), which have a minimum operating supply voltage of 1.7V (V_{IN} LDO_x). The control registers and some input circuitry operate from the main system supply (MBATT) and hold their contents when the regulator input voltage (V_{IN}_{LDOx}) drops to 0V.

The NMOS regulators (NDRVx) gate drive operates from the main system supply (MBATT), while the load current is provided by the regulator input (IN_LDOxx). The input voltage ($V_{IN\ LDOX}$) for the NMOS regulators extends down to 0.8V. To provide adequate gate drive for the NMOS output device, the NMOS output voltage should be more than 1.5V lower than the main system supply voltage (V_{MBATT}). The control registers are also powered from MBATT.

NMOS regulators works into dropout with the V_{IN LDOx} to V_{OUTLDOx} voltage determined by I_{LOAD} x R_{DO} where R_{DO} is the dropout resistance (typically 200mW). As dropout voltage decreases (by reducing load) below 0.3V, the PSRR and load regulation degrades.

All PMOS regulators are compensated at their output and require a remote output capacitance large enough to prevent oscillation. The NMOS regulators are internally compensated, but an additional output capacitor can be added to improve immunity to high-frequency noise and allow stable low-power mode operation. See the *[Output Capacitor Selection](#page-65-0)* section for additional information.

Table 5. Basic LDO Topologies

Figure 13. Linear Regulator Functional Diagram

Active-Discharge Resistor

Each linear regulator has an active-discharge resistor feature that can be enabled/disabled with ADE_Lx_. Enabling the active discharge feature helps ensure a complete and timely power-down of all system peripherals. The default condition of the active-discharge resistor feature is enabled so that whenever VMBATT is below VMBATTUVLO all regulators are disabled with their active-discharge resistors turned on. When V_{MBATT} is less than 1.0V, the NMOS transistors that control the active-discharge resistors lose their gate drive and become open.

Input Capacitor Selection

Sufficient input bypass capacitance is required for stable operation of the LDO. Choose an effective input bypass capacitance (C_{IN-LDO}) of at least 1µF after derating. A 2.2µF ceramic capacitor is sufficient for most use cases. Larger values of C_{IN} $LD\overline{O}$ improve the decoupling for the LDO regulator.

 C_{IN} LDO reduces the current peaks drawn from the battery or input power source during LDO regulator operation. The impedance of the input capacitor should be very low (i.e., ≤ 5mΩ + ≤ 500pH) for frequencies up to 2MHz. Ceramic capacitors with X5R or X7R dielectric are highly recommended due to their small size, low ESR, and small temperature coefficients.

As the case sizes of ceramic surface-mount capacitors decrease, their capacitance verses DC bias voltage characteristic becomes poor. Due to this characteristic, it is possible for 0603 case size capacitors to perform well while 0402 case size capacitors of the same value perform poorly. Consider the input capacitance value after initial tolerance, bias voltage, aging, and temperature derating. Analog Devices recommends a nominal capacitance value of 1μF which, in 0402 case size, can derate to 0.4μF.

Output Capacitor Selection

Choose the output bypass capacitance (C_{OUT}_{LDO}) to be 2.2µF. Larger values of C_{OUTLDO} improve PSRR and load transient performance but increases the input surge currents during soft-start and output voltage changes.

COUTLIDO is required to keep the LDO stable. The impedance of the output capacitor should be very low (i.e., $\leq 5m\Omega$ + ≤ 500pH) for frequencies up to 2MHz. Ceramic capacitors with X5R or X7R dielectric are highly recommended due to their small size, low ESR, and small temperature coefficients.

As the case sizes of ceramic surface-mount capacitors decrease, their capacitance verses DC bias voltage characteristic becomes poor. Due to this characteristic, it is possible for 0603 case size capacitors to perform well while 0402 case size capacitors of the same value perform poorly. Consider the output capacitance value after initial tolerance, bias voltage, aging, and temperature derating. Analog Devices recommends a nominal capacitance value of 2.2μF which, in 0402 case size, can derate to 1.1μF.

P-Channel Linear Regulator Output Capacitor

P-channel LDOs require an output capacitor to maintain stable output voltage regulation. Adjustable compensation allows for flexibility when designing the PCB and placing the output capacitor. The default compensation is factory programmable; additionally, the compensation is register adjustable when the LDO is off.

In many LDO designs, there is little-to-no flexibility in the physical placement of the output capacitor on the PCB. However, the LDO implementation within the device provides adjustable compensation for the p-channel LDOs. This adjustable compensation allows flexibility in the placement of the output capacitor on the PCB. However, as the output capacitor is placed farther from the device, slower compensation values are required to maintain stability; these slower compensation values decrease performance.

For optimum p-channel LDO performance, place the output capacitor as close to the LDO output as possible and program COMP_Lx = 0b00. In situations were the full LDO performance is not required, the output capacitor can be place farther away from the LDO output with slower compensation values. This option becomes especially useful when the LDO output capacitor can be eliminated and the load's local input capacitor becomes the only capacitance on the LDO output node.

Warning: The COMP_Lx bits should only be changed when the LDO is disabled. If the compensation bits are changed when the LDO is enabled, the output voltage glitches as the compensation changes.

N-Channel Linear Regulator Output Capacitor

N-channel LDOs technically do not require and output capacitor to maintain stable output voltage regulation if they are in normal mode (i.e., they can be capless). However, a n-channel LDO does require an output capacitor to maintain stable output voltage regulation in low-power mode. In either mode (normal or low-power), the LDO performs best with an output capacitor (COUTx) as recommended in the *[Output Capacitor Selection](#page-65-0)* section of the datasheet.

Note that the COMP_Lx[1:0] bits for n-channel LDOs must be set to 0b00.

Bias

A small section of bias circuitry is required to be on when any of the LDOs are enabled. LDO enable signal from the FPS OR the L_B_EN from I²C enables the LDO bias circuits. In addition, whenever the LDO bias is enabled, the global bias for the MAX77714 is also enabled. The LDO bias circuitry takes t_{LBIAS} to turn on. If the LDO bias circuit is off and an LDO is enabled, the total time before the output starts slewing up is $t_{LB|AS} + t_{LON}$. If the LDO bias is on and an LDO is enabled, the total time before the output starts slewing is t_l ON.

If the sequencing of a group of regulators is particularly important, it may be desirable to force the LDO bias to be on with the L_B_EN bit to ensure that the LDOs enables in a consistent manner with the shortest latency. Note that whenever L_B_EN is set, the global bias circuits and LDO bias circuits are enabled. The combined bias circuitry current is I_{OBIAS} . To ensure that the system always operates with the lowest quiescent current possible, it is a good idea to clear L_B_EN when it is not needed.

LDO Power Modes

Linear regulators and step-down regulators have very similar power mode controls. Each linear regulator is independently controlled with PWR_MD_Lx[1:0] and each step-down regulator is independently controlled with PWR_MD_SDx[1:0]. In addition to enable and disable control, each linear regulator has a special low-power mode that reduced the quiescent current to 1.5µA. In low-power mode, each regulator supports a load of up to 5mA (I_{.MAXxx}). The load regulation performance degrades proportionally with the reduced load current.

Several usage options are available for low-power mode. To force individual regulators to low-power mode, set PWR_MD_Lx to 0b10. To force a group of regulators to enter and exit low-power mode in unison, set their individual PWR_MD_Lx_ bits to 0b10. When set for this "group and/or dynamic" low-power mode, the low-power mode is enabled when the global low-power mode signal is high. The global low-power mode signal is driven by the GLBL LPM bit or though a GPIO0.

When a linear regulator is configured to be part of a flexible power sequence (FPSSRC_Lx), the power mode bits (PWR_MD_Lx) are still used to configure low-power mode and normal-power mode, but the flexible power sequencer itself controls weather the regulator is enabled or disabled.

Soft-Start and Dynamic Voltage Scaling (DVS)

The linear regulators have a programmable soft-start rate. When a linear regulator is enabled, the output voltage ramps to its final voltage at a slew rate of either 5mV/ms or 100mV/ms, depending on the state of the SS_Lx bit. The 5mV/ms ramp rate limits the input inrush current to around 10mA on a 300mA regulator with a 2.2µF output capacitor and no load. The 100mV/ms ramp rate results in a 200mA inrush current on a 300mA regulator with a 2.2µF output capacitor and no load, but achieves regulation within 50ms. The soft-start ramp rate is also the rate of change at the output when changing dynamically between two output voltages while enabled (DVS). This includes both positive and negative output voltage transitions.

The LDO soft-start circuitry supports starting into a prebiased output. For example, if the output capacitor has an initial voltage of 0.4V when the regulator is enabled, the regulator gracefully increases the capacitor voltage to the required target voltage such as 1.2V. This is unlike other regulators without the start into prebias feature where they can force the output capacitor voltage to 0V before the soft-start ramp begins.

During a soft-start event or a DVS transition, the regulators output current increases by C_{OUT} x dV/dt. In the event that the load current plus the additional current imposed by the soft-start or DVS transition, reach the regulator's current limit, the current limit is enforced. When the current limit is enforced, the advertised transition rate (dV/dt) does not occur.

Power-OK (POK) Comparators for Linear Regulators

Each linear regulator includes a POK comparator. The POK comparator signals (POK_Lx) indicate when each output has lost regulation (i.e., the output voltage is below V_{POKTHL}). The POK signal has a 25µs noise immunity filter (t_{POKNFLDO}). When any of the POK signals (POK Lx) go low, a maskable interrupt is generated. POK is the only interrupt available for the device's LDOs. The block level LDO interrupt register is IRQ_LVL2_Lx and the top level LDO interrupt is IRQ_LDO.

Overvoltage Clamp

Each LDO has an overvoltage clamp that allows it to sink current when the output voltage is above its target voltage. This

overvoltage clamp for a given LDO is disabled when that LDO is in low-power mode. If an LDO is in normal-power mode, then the overvoltage clamp is enabled/disabled with OVCLMP_EN_Lx (default enabled). The following bulleted list briefly describes three typical application scenarios that pertain to the overvoltage clamp.

Warning: If an LDO's overvoltage clamp is disabled (OVCLMP_EN_Lx = 0), the output loading is very low (<10µA), and the junction temperature of the device is hot (>70°C) the output voltage may rise above its regulation point.

Typical application scenarios for the overvoltage clamp:

- LDOs Load Leaking Current into the LDOs Output. Some LDO loads leak current into an LDO output during certain operating modes. This is typically seen with microprocessor loads. For example, a microprocessor with 3.3V, 2.5V, 1.8V, and 1.0V supply rails is running in standby mode. In this mode the higher voltage rails can leak currents of several milliamps into the lower voltage rails. If the 1.0V rail is supplied by an LDO, the LDO output voltage rises based on the amount of leakage current. With the LDO overvoltage clamp enabled, when the output voltage rises above its target regulation voltage, the overvoltage clamp sinks current from the output capacitor, which brings the output voltage back within regulation.
- Negative Load Transient to 0A: When the LDO load current quickly ramps to 0A (i.e., 300mA to 0A load transient with 1µs transition time), the output voltage can overshoot (i.e., sore). Since the LDO cannot turn off its pass device with an intently fast load transition, the LDO output voltage overshoots. In this instance, when the output voltage sores above target regulation voltage, the overvoltage clamp sinks current from the output capacitor, which brings the output voltage back within regulation.
- Negative Dynamic Voltage Transition: When the LDO output target voltage is decreased (i.e., 1.2V to 0.8V) when the system loading is light, the energy in the output capacitor tends to hold the output voltage up. When the output voltage is above its target regulation voltage, the overvoltage clamp sinks current from the output capacitor, which brings the output voltage back within regulation.

Nontypical Applications:

There are some nontypical applications for this overvoltage clamp that are not discussed.

- Two LDO outputs can be connected together to give one output with more current capability. In this case, you typically want one LDOs output voltage to be set 1LSB higher than the other LDO. The LDO with the lower output voltage should deactivate its overvoltage clamp.
- Similar to the above, a step-down and LDO output can be connected together to give more current. In this case, the LDO output should be set lower than the step-down so that the step-down delivers the bulk of the load current (i.e., step-down is more efficient). The LDO would only become active during transient conditions or high load condiditons. In this case, the LDO overvoltage clamp should be disabled.

Detailed Description—GPIO

GPIO

The MAX77714 has eight GPIO channels. It can be configure as GPO, GPI, and also has an ALT mode.

When configured as a general purpose output (GPO), the GPO is programmable to be push-pull or open-drain. When a GPIO is configured as a general purpose output, do not enable the internal pull-up or internal pull-down resistors which corresponds with that GPO.

When configured as a general pupose input (GPI), the GPI is programmable to have either a high-impedance, 100kΩ pulldown, or 100kΩ pullup. Additionally, interrupt inputs with programmable debounce timers are available.

The GPI edge(s) that triggers interrupts are selectable with REFE_IRQx. When a GPI interrupt is enabled and the selected edge(s) are detected, EDGEx is set in the INT LVL2 GPIO register and IRQ GPIO is set in the top-level interrupt register. If the top-level interrupt mask is cleared (IRQ_GPIOM), the external interrupt signal nIRQ is asserted.

Alternate Mode

In addition to the GPO and GPI configurations, each GPIO has an alternate mode.

When a GPIO is in an alternate mode device may internally force the direction (i.e., output or input) and/or logic level of the GPIO. However, other options such as debounce times and rising/falling edge triggered interrupt settings are still valid in alternate mode.

Table 6. GPIO Alternate Modes

Features and Benefits

- Eight GPIO
- MBATT and GPIO INB Input Power Sources
- Four GPIOs per input
- Input Voltage Range from 1.7V to 5.5V
- GPI
	- GPI to ACOK
	- GPI
	- Flexible Edge Trigger Support
	- Selectable Debounce Time
	- Optional pullup/pulldown
- GPO
	- Push-Pull
	- Open-Drain
	- Four GPO programmable to Flexible Power Sequencer
	- Three GPO to 32kHz Output Option
	- 12mA Sink Current Allows for LED Drive

GPIO Programming Matrix

Table 7. GPIO Programming Matrix

Detailed Description—32kHz Oscillator

The MAX77714 provides a 32kHz clock signal for the real-time clock and the central state machine. The 32kHz clock signal is derived from either an external 32kHz crystal or an external 32kHz clock source.

Features: 32kHz Oscillator

- Low-jitter mode reduces cycle-to-cycle jitter to 15ns
- Low-power mode lowers power consumption
- Dedicated clock output, additional outputs selectable as GPIO alternate modes
- Allows use of board-mounted crystal ballast capacitors or on-chip crystal ballast capacitors
- Internal ballast capacitor options support 6.5pF, 7.5pF, and 12.5pF crystals
- Bypass mode supports external clock input
- Backup silicon oscillator allows continued functionality if crystal fails

Operation Modes

The MAX77714 32kHz oscillator supports two hardware configurations, selectable by an OTP option. In normal mode, the oscillator drives an external crystal to derive a 32kHz clock signal. In bypass mode, the oscillator accepts a 32kHz square wave from an external clock source. CRYSTAL CONFIG indicates the active operation mode.

In bypass mode, the oscillator buffers and passes through the input clock. The frequency detector detects abnormally low or high frequencies (below fDET_MIN and above fDET_MAX), but does not consider duty cycle or jitter.

Figure 14. Block Diagram—32kHz Normal-Mode Operation

Low-Jitter Mode and Low-Power Mode

The crystal driver features two modes of operation: low-power mode and low-jitter mode. In low-jitter mode, the crystal driver current consumption is 24μA which allows for 15ns cycle-to-cycle jitter (tJIT_LPM) and duty cycle to between 45% and 55%. In low-power mode, the crystal driver current consumption is low (IOSC_LPM, 1.5μA) which corresponds to an increased cycle-to-cycle jitter and wider duty cycle (40% to 60%).

Power mode control is independently managed by the ON/OFF Controller based on the system state (ACTIVE, HIBERNATE, and STANDBY). When a system state transition occurs, the crystal driver automatically changes power mode as configured with 32K_LJ_x.

Internal Ballast Capacitors

The crystal driver has four options for internal ballast capacitance, selectable with an OTP option (32KLOAD_OTP). [\(Table 8\)](#page-71-0) shows the total crystal load capacitance (internal and external) for common configurations. XIN and XOUT typically have 3pf of parasitic capacitance each (C_{PAR}) which factors in the total load capacitance calculation. For any internal and external load capacitance configuration, C_{LOAD} can be calculated using the formula $C_{\text{LOAD}} = (C_{\text{INT}} + C_{\text{EXT}})$ $+ C_{\text{PAR}}$) / 2.

Changing the internal load capacitance while the system is in operation is not recommended.

Table 8. 32kHz Crystal Oscillator Load Capacitance

Buffered Output

The oscillator clocks a dedicated 32kHz buffered output (32KOUT) which provides a low-jitter 32kHz clock source to the system. The buffer is configurable to be either a push-pull, or open-drain output stage. The supply for the push-pull output stage is configurable to be one of three voltage rails: LDO12, BUCK3 or LSW1 (V32KOUT). For the buffered output to meet the low-jitter spec (t-JIT_LPM), the following conditions must be satisfied:

- The primary oscillator must generate the 32kHz clock (32KSOURCE = 0).
- If a crystal is used (normal mode), the oscillator must be configured for low-jitter operation.
- If an external clock is used (bypass mode), the external clock must meet the low-jitter spec.
- The buffer must be configured for the push-pull output stage.

Additional 32kHz outputs are available from GPIO alternative modes; see the *[GPIO](#page-68-0)* section for more information.

The FBB3 and LSW1 supply inputs to the buffer can be unpowered when their respective inputs are disabled. In such cases, the unpowered inputs are not backpowered from the powered inputs. Before enabling the buffer (EN32KOUT = 1), the selected supply must have reached its programmed output voltage; otherwise, runt pulses may appear at 32KOUT.

Silicon Oscillator

The MAX77714 includes a silicon oscillator which permits continued system operation in the event that the crystal oscillator fails. The silicon oscillator has reduced accuracy and higher jitter than a crystal oscillator and is not suitable for timekeeping or applications requiring low jitter; however, it offers greater reliability than the crystal oscillator and is sufficiently accurate for continued operation of device's core functionality.

During normal operation, the device derives its 32kHz clock from the crystal oscillator or internal silicon oscillator
depending on the oscillator OTP selection. There are two conditions that cause it to use the silicon oscillator instead: if the crystal oscillator fails to start up in a timely manner, or if it fails during operation. The latter case results in an asynchronous reset of all registers in the device. In both cases, the device generates an interrupt (XTAL_FAIL_I) to notify the AP that a crystal fault caused the device to start up and operate using the silicon oscillator.

Once the system is operating with the silicon oscillator, software can periodically check XOSCOK to see if the crystal has restabilized. If software determines that the crystal is stable enough to use, it can set XOSC_RETRY to initiate a glitchless transition back to the crystal oscillator. If the crystal oscillator is not OK (XOSCOK = 0), the transition does not occur.

Figure 15. Flow Chart—Silicon Oscillator

Detailed Description—Backup Battery Charger

The backup battery charger is a constant voltage (CV) and constant current (CC) style charger with a series output resistance. The backup battery charger is enabled and disabled with BBCEN. The charge current, charger voltage, output current, and output resistance are adjustable with the CNFG_BBC register. The backup battery charger is suitable for the following types of backup cells:

- Super capacitor (a.k.a., gold cap, double-layer electrolytic)
- Standard capacitors (tantalum, electrolytic, ceramic)

● Rechargeable lithium manganese cells

Features

- 800µA maximum CC-CV backup battery charger.
- 2.5V to 3.5V adjustable backup battery setting with $± 3\%$ tolerance.
- Seamless transition of RTC supply from V_{MBATT} to V_{BBATT} when V_{MBATT} drops below V_{MBATT} UVLO threshold.

Detailed Description—Real-Time Clock (RTC)

The real-time clock (RTC) is responsible for keeping track of the time. It records seconds, minutes, hours, days, months, and years with a calendar structure that accounts for leap years. The RTC is further equipped with two alarms and has a host of maskable capabilities.

Through a set of configuration registers, various modes of operation are possible. RTC supports both "Binary", and "Binary Coded Decimal", and supports features such as AM/PM, and 24/12 modes of operation. Additional sudden momentary power loss (SMPL) is available.

Features

- Gregorian Calendar with Leap Year Correction
- Two Alarms
- Maskable Interrupts
	- 1s and 60s
	- Alarm 1 & 2
	- SMPL
- Binary and BCD Modes
- 12/24 Hour Modes
- Sudden Momentary Power Loss (SMPL)
- Double Buffered Read/Write Registers Allows Asynchronous Register Access
- Operates down to 1.71V

Writing to RTC

In order to safely write to various registers on-board the RTC, all RTC registers (except RTCINT register, bit 0 of UPDATE0 register, and bit 4 of UPDATE0 register) have a corresponding "Write Buffer". When the user writes to the RTC, the user is actually performing a write to these "Write Buffers". Therefore, in writing to RTC there are two steps needed to update a particular register or set of registers:

- 1. User writes desired value(s) to the register(s) located between 0x01 and 0x24. Behind the scene, only the "Write Buffers" are updated with these new values.
- 2. The user then writes a 1 to UDR bit 0 of the "UPDATE0 Register" at address 0x04 to transfer the modified "Write Buffers" to the corresponding time registers.

The logic subsequently would perform a transfer of data from Write Buffers to the actual registers and then clears the "UDR" bit automatically as well as clearing the Write Buffers (marking them as not modified).

Under the hood, the logic first does a double synchronization of the UDR bit to the 32.768kHz clock before using it as an enable bit to transfer from Write buffers to the actual registers thus allowing a safe update of these two unsynchronized clock events.

Example 1. Pseudo code for setting clock to Saturday, Jan 01, 2011, 1:00:00 PM

Reading from RTC

Corresponding to most timing registers are a series of Read Buffers.

In order to safely read from various registers on-board the RTC, all RTC registers (except RTCINT register and bit 0 and 4 of UPDATE0 Register) have a corresponding Read Buffer. When the user reads from the RTC, the user is actually performing a read from the Read Buffers. Therefore, there are two steps needed to read a particular register or set of registers:

- 1. The user writes a 1 to RBUDR bit 4 of the UPDATE0 Register at address 0x04 to transfer most timing registers to the Read Buffers. Behind the scene, the Read Buffers are updated.
- 2. The user then reads from the desired register location.

After step 1, the logic subsequently performs a transfer of data from the actual registers to the Read Buffers and then clears the RBUDR bit.

The logic first does a double synchronization of the RBUDR bit to the 32.768 kHz clock before using it as a clock (RBUDR_sync) to transfer from the actual registers to the Read Buffers, thus allowing a safe update of these 2 unsynchronized clock events.

Example 3. Pseudo code for reading the time:

Set RTCUPDATE0 to 0x10 //transfer timekeeper counters to read buffers

Wait 16ms for read to complete

Read RTCDOM //Day of Month **Example 4.** Pseudo code for reading ALARM1 setting: Set RTCUPDATE0 to 0x10 // transfer timekeeper counters to read buffers Wait 16ms for read to complete Read RTCSECA1 //sec Read RTCMINA1 //minute Read RTCHOURA1 //hour Read RTCDOWA1 //Day of Week Read RTCMONTHA1 //Month Read RTCYEARA1 //Year Read RTCDOMA1 //Day of Month

Sudden Momentary Power Loss (SMPL)

The SMPL function allows the system to recover if power is briefly lost due to a poor battery connection. If V_{MBATT} falls below and returns above the UVLO threshold within the SMPL timer threshold (SMPLT[1:0]) and SMPL is enabled (SMPL_EN = 1), SMPL initiates a power-up sequence and the SMPL interrupt bit is set. If the SMPL timer expires before V_{MBATT} returns, the SMPL enable bit is automatically cleared in order to prevent power-up on subsequent SMPL events.

To ensure proper operation of the SMPL state machine, initialization software should clear and set SMPL_EN after each power on event.

Detailed Description—I2C Interface

I 2C Slave Address

The device implements 7-bit slave addressing. An $12C$ bus master initiates communication with a slave device by issuing a START condition followed by the slave address. The device responds to its two slave addresses; all other slave addresses are not acknowledged by the device, (optional) with the exception of the General Call address (Software Reset option).

Table 9. MAX77714 Slave Addresses

Register Map

RTC

Register Details

[RTCINT \(0x00\)](#page-76-0)

[RTCINTM \(0x01\)](#page-76-0)

[RTCCNTLM \(0x02\)](#page-76-0)

[RTCCNTL \(0x03\)](#page-76-0)

[RTCUPDATE0 \(0x04\)](#page-76-0)

[RTCUPDATE1 \(0x05\)](#page-76-0)

[RTCSMPL \(0x06\)](#page-76-0)

[RTCSEC \(0x07\)](#page-76-0)

[RTCMIN \(0x08\)](#page-76-0)

[RTCHOUR \(0x09\)](#page-76-0)

[RTCDOW \(0x0A\)](#page-76-0)

[RTCMONTH \(0x0B\)](#page-76-0)

[RTCYEAR \(0x0C\)](#page-76-0)

[RTCDOM \(0x0D\)](#page-76-0)

[RTCSECA1 \(0x0E\)](#page-76-0)

[RTCMINA1 \(0x0F\)](#page-76-0)

[RTCHOURA1 \(0x10\)](#page-76-0)

[RTCDOWA1 \(0x11\)](#page-76-0)

[RTCMONTHA1 \(0x12\)](#page-76-0)

[RTCYEARA1 \(0x13\)](#page-76-0)

[RTCDOMA1 \(0x14\)](#page-76-0)

[RTCSECA2 \(0x15\)](#page-76-0)

[RTCMINA2 \(0x16\)](#page-76-0)

[RTCHOURA2 \(0x17\)](#page-76-0)

[RTCDOWA2 \(0x18\)](#page-76-0)

[RTCMONTHA2 \(0x19\)](#page-76-0)

[RTCYEARA2 \(0x1A\)](#page-76-0)

[RTCDOMA2 \(0x1B\)](#page-76-0)

[RTC_TIME_OK \(0x25\)](#page-76-0)

PMIC-GPIO

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Register Details

[INT_TOP \(0x00\)](#page-91-1)

[INT_MBATTRST_TEMP \(0x01\)](#page-91-1)

[INT_LVL2_ONOFF \(0x02\)](#page-91-1)

[INT_LVL2_SD0_3 \(0x03\)](#page-91-1)

[INT_LVL2_L0_7 \(0x04\)](#page-91-1)

[INT_LVL2_L8 \(0x05\)](#page-91-1)

[INT_LVL2_GPIO \(0x06\)](#page-91-1)

[INT_TOPM \(0x07\)](#page-91-1)

[INTM_MBATTRST_TEMP \(0x08\)](#page-91-1)

[INTM_ONOFF \(0x09\)](#page-91-1)

[INTM_SD0_3 \(0x0A\)](#page-91-1)

[INT_MSK_L0_7 \(0x0B\)](#page-91-1)

[INT_MSK_L8 \(0x0C\)](#page-91-1)

[STAT_MBATTRST_TEMP \(0x0D\)](#page-91-1)

[STAT_ONOFF \(0x0E\)](#page-91-1)

[POERC0 \(0x10\)](#page-91-1)

[POERC1 \(0x11\)](#page-91-1)

[STAT_SD0_3 \(0x20\)](#page-91-1)

[32K_STATUS \(0x30\)](#page-91-1)

[32K_CONFIG \(0x31\)](#page-91-1)

[CNFG_GLBL1 \(0x90\)](#page-91-1)

[CNFG_GLBL2 \(0x91\)](#page-91-0)

[CNFG_GLBL3 \(0x92\)](#page-91-0)

[CNFG1_ONOFF \(0x93\)](#page-91-0)

[CNFG2_ONOFF \(0x94\)](#page-91-0)

[MSTR_PU_PD \(0x95\)](#page-91-0)

[MSTR_SLPENTRY_EXIT \(0x96\)](#page-91-0)

[BUCK_PWR_MD \(0x97\)](#page-91-0)

[LDO_PWR_MD0_3 \(0x98\)](#page-91-0)

[LDO_PWR_MD4_7 \(0x99\)](#page-91-0)

[LDO_PWR_MD8 \(0x9A\)](#page-91-0)

[LDO0FPS \(0x9B\)](#page-91-0)

[LDO1FPS \(0x9C\)](#page-91-0)

[LDO2FPS \(0x9D\)](#page-91-0)

[LDO3FPS \(0x9E\)](#page-91-0)

[LDO4FPS \(0x9F\)](#page-91-0)

[LDO5FPS \(0xA0\)](#page-91-0)

[LDO6FPS \(0xA1\)](#page-91-0)

[LDO7FPS \(0xA2\)](#page-91-0)

[LDO8FPS \(0xA3\)](#page-91-0)

[SD0FPS \(0xA4\)](#page-91-0)

[SD1FPS \(0xA5\)](#page-91-0)

[SD2FPS \(0xA6\)](#page-91-0)

[SD3FPS \(0xA7\)](#page-91-0)

[GPIO0FPS \(0xA8\)](#page-91-0)

[GPIO1FPS \(0xA9\)](#page-91-0)

[GPIO2FPS \(0xAA\)](#page-91-0)

[GPIO7FPS \(0xAB\)](#page-91-0)

[RSTIOFPS \(0xAC\)](#page-91-0)

[SD0_CNFG1 \(0x40\)](#page-91-0)

[SD1_CNFG1 \(0x41\)](#page-91-0)

[SD2_CNFG1 \(0x42\)](#page-91-0)

[SD3_CNFG1 \(0x43\)](#page-91-0)

[SD0_CNFG2 \(0x44\)](#page-91-0)

[SD0_CNFG3 \(0x45\)](#page-91-0)

[SD1_CNFG2 \(0x46\)](#page-91-0)

[SD1_CNFG3 \(0x47\)](#page-91-0)

[SD2_CNFG2 \(0x48\)](#page-91-0)

[SD2_CNFG3 \(0x49\)](#page-91-0)

[SD3_CNFG2 \(0x4A\)](#page-91-0)

[SD3_CNFG3 \(0x4B\)](#page-91-0)

[LDO_CNFG1_L0 \(0x50\)](#page-91-0)

[LDO_CNFG2_L0 \(0x51\)](#page-91-0)

[LDO_CNFG1_L1 \(0x52\)](#page-91-0)

[LDO_CNFG2_L1 \(0x53\)](#page-91-0)

[LDO_CNFG1_L2 \(0x54\)](#page-91-0)

[LDO_CNFG2_L2 \(0x55\)](#page-91-0)

[LDO_CNFG1_L3 \(0x56\)](#page-91-0)

[LDO_CNFG2_L3 \(0x57\)](#page-91-0)

[LDO_CNFG1_L4 \(0x58\)](#page-91-0)

[LDO_CNFG2_L4 \(0x59\)](#page-91-0)

[LDO_CNFG1_L5 \(0x5A\)](#page-91-0)

[LDO_CNFG2_L5 \(0x5B\)](#page-91-0)

[LDO_CNFG1_L6 \(0x5C\)](#page-91-0)

[LDO_CNFG2_L6 \(0x5D\)](#page-91-0)

[LDO_CNFG1_L7 \(0x5E\)](#page-91-0)

[LDO_CNFG2_L7 \(0x5F\)](#page-91-0)

[LDO_CNFG1_L8 \(0x60\)](#page-91-0)

[LDO_CNFG2_L8 \(0x61\)](#page-91-0)

[LDO_CNFG3 \(0x62\)](#page-91-0)

[CNFG_GPIO0 \(0x70\)](#page-91-0)

[CNFG_GPIO1 \(0x71\)](#page-91-0)

[CNFG_GPIO2 \(0x72\)](#page-91-0)

[CNFG_GPIO3 \(0x73\)](#page-91-0)

[CNFG_GPIO4 \(0x74\)](#page-91-0)

[CNFG_GPIO5 \(0x75\)](#page-91-0)

[CNFG_GPIO6 \(0x76\)](#page-91-0)

[CNFG_GPIO7 \(0x77\)](#page-91-0)

[PUE_GPIO \(0x78\)](#page-91-0)

[PDE_GPIO \(0x79\)](#page-91-0)

[AME_GPIO \(0x7A\)](#page-91-0)

[CID0 \(0xB0\)](#page-91-0)

[CID1 \(0xB1\)](#page-91-0)

[CID2 \(0xB2\)](#page-91-0)

[CID3 \(0xB3\)](#page-91-0)

[CID4 \(0xB4\)](#page-91-0)

[CNFG_BBC \(0x80\)](#page-91-0)

[I2C_CTRL1 \(0xC0\)](#page-91-0)

[I2C_CTRL2 \(0xC1\)](#page-91-0)

Typical Application Circuit

Ordering Information

+Denotes a lead(Pb)-free/RoHS-compliant package.

T = Tape and reel.

Revision History

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